



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name :

ELECTRONICS REGIONAL TEST LABORATORY (WEST), GOVERNMENT OF INDIA,
MINISTRY OF ELECTRONICS & INFORMATION TECHNOLOGY, STQC
DIRECTORATE, PLOT NO. F-7 & 8, MIDC AREA, ANDHERI (EAST), MUMBAI,
MAHARASHTRA, INDIA

Accreditation Standard

ISO/IEC 17025:2017

Certificate Number

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Validity

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S.No	Discipline / Group	Measurand or Reference Material/Type of instrument or material to be calibrated or measured / Quantity Measured /Instrument	Calibration or Measurement Method or procedure	Measurement range and additional parameters where applicable(Range and Frequency)	* Calibration and Measurement Capability(CMC)(±)
Permanent Facility					
1	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	3 Phase Active Power @ 40 Hz to 70 Hz (30 V to 250 V, 10 mA to 12 A, 0.1 PF (Lag/Lead) to UPF)	Using Power Energy Standard by Direct Method	0.09 W to 9 kW	0.2 % to 0.027 %
2	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	1 Phase AC Active Energy @ 40 Hz to 70 Hz (30 V to 500 V, 10 mA to 100 A, 0.1 PF (Lag/Lead) to UPF	Using Power Energy Standard by Direct Method	0.03 Wh to 50 kWh	0.2 % to 0.02 %
3	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	1 Phase AC Active Power @ 40 Hz to 70 Hz (30 V to 500 V, 10 mA to 100 A, 0.1 PF (Lag/Lead) to UPF)	Using Power Energy Standard by Direct Method	0.03 W to 50 kW	0.2 % to 0.02 %
4	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	3 Phase Active Energy @ 40 Hz to 70 Hz) (40 V to 320 V,10 mA to 20 A, 0.1 PF (Lag/Lead) to UPF)	Using Power Energy Calibrator by Direct Method	0.12 Wh to 19.2 kWh	0.023 % to 0.21 %



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5	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	3 Phase Active Energy @ 40 Hz to 70 Hz, (30 V to 500 V, 10 mA to 100 A, 0.1 PF (Lag/Lead) to UPF)	Using Power Energy Standard by Direct Method	0.09 Wh to 150 kWh	0.2 % to 0.02 %
6	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 1 kHz to 5 kHz	Using 8½ DMM, AC Measurement Standard and Standard Resistor by V/I Method	10 µA to 100 µA	0.2 % to 0.05 %
7	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 1 kHz to 5 kHz	Using 8½ DMM and Standard Resistor by V/I Method	100 µA to 100 mA	0.05 % to 0.03 %
8	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 1 kHz to 5 kHz	Using 8½ DMM and Standard Resistor by V/I Method	100 mA to 20 A	0.03 % to 0.09 %
9	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 10 Hz to 1 kHz	Using AC Measurement Standard & Std. Resistor by V/I Method)	10 µA to 100 mA	0.015 % to 0.025 %



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10	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 10 Hz to 1 kHz	Using 8½ DMM and Standard Resistor by V/I Method	10 A to 100 A	0.02 % to 0.05 %
11	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 10 Hz to 1 kHz	Using 8½ DMM and Standard Resistor by V/I Method	100 mA to 10 A	0.01 % to 0.02 %
12	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 5 kHz to 10 kHz	Using AC Measurement System & AC Shunts by V/I Method	1 mA to 2 A	0.01 % to 0.025 %
13	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 5 kHz to 10 kHz	Using AC Measurement System & AC Shunts by V/I Method	2 A to 10 A	0.03 %
14	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 50 Hz	Using CT, 8½ DMM and Standard Resistor by V/I Method	1 A to 3200 A	0.2 %



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15	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC High Voltage @ 50 Hz	Using HV Probe with DMM by Direct Method	1 kV to 28 kV	0.5 % to 1 %
16	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC High Voltage @ 50 Hz	Using HV Divider with DMM by Direct Method	35 kV to 50 kV	1.8 %
17	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Resistance (4 Wire) @ 1 kHz	Using MFC, Standard Resistor & 8½ Digit DMM by Substitution Method	0.1 mohm to 100 mohm	0.02 % to 0.01 %
18	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Resistance (4 Wire) @ 1 kHz	Using MFC, Standard Resistor & 8½ Digit DMM by Substitution Method	1 ohm to 10 kohm	0.004 %
19	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Resistance (4 Wire) @ 1 kHz	Using MFC, Standard Resistor & 8½ Digit DMM by Substitution Method	100 mohm to 1 ohm	0.01 % to 0.004 %



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20	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 10 Hz to 10 kHz	Using AC Measurement System by Direct Method	1 mV to 100 mV	0.2 % to 0.015 %
21	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 10 Hz to 10 kHz	Using AC Measurement System by Direct Method	100 mV to 10 V	0.015 % to 0.004 %
22	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 10 kHz	Using AC Measurement System by Direct Method	10 V to 1000 V	0.004 % to 0.009 %
23	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 10 kHz to 20 kHz	Using AC Measurement System by Direct Method	10 V to 1000 V	0.005 % to 0.009 %
24	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 10 kHz to 30 kHz	Using AC Measurement System by Direct Method	1 mV to 100 mV	0.16 % to 0.009 %



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25	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 10 kHz to 30 kHz	Using AC Measurement System by Direct Method	100 mV to 10 V	0.009 % to 0.005 %
26	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 100 kHz to 1 MHz	Using AC Measurement System by Direct Method	1 mV to 10 V	1.4 % to 0.21 %
27	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 30 kHz to 100 kHz	Using AC Measurement System by Direct Method	1 mV to 100 mV	0.3 % to 0.0093 %
28	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 30 kHz to 100 kHz	Using AC Measurement System by Direct Method	10 V to 200 V	0.005 % to 0.09 %
29	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 30 kHz to 100 kHz	Using AC Measurement System by Direct Method	100 mV to 10 V	0.009 % to 0.005 %



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30	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 40 Hz to 10 kHz	Using AC Measurement Standard by Direct Method	10 V to 1000 V	0.004 % to 0.009 %
31	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	Capacitance @ 1 kHz	Using Video Bridge by Direct Method	1 μ F to 10 mF	0.01 % to 0.05 %
32	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	Capacitance @ 1 kHz	Using Video Bridge by Direct Method	1 pF to 10 pF	0.05 % to 0.1 %
33	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	Capacitance @ 1 kHz	Using Video Bridge by Direct Method	10 pF to 1000 pF	0.1 %
34	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	Capacitance @ 1 kHz	Using Video Bridge by Direct Method	1000 pF to 1 μ F	0.1 % to 0.034 %



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35	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	Capacitance @ 100 Hz	Using Video Bridge by Direct Method	10 mF to 1000 mF	0.05 %
36	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	CT Phase Angle @ 50 Hz	Using CT Test Bench & Standard CT by Comparison Method	0 to 360 min	3 min
37	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	CT Ratio @ 50 Hz	Using CT Test Bench & Standard CT by Comparison Method	1 A to 3200 A / 1 A or 5 A	0.2 %
38	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	Inductance @ 1 kHz	Using Video Bridge & Component Analyser by Direct Method	100 µH to 10 H	0.052 % to 0.055 %
39	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	Phase Angle @ 40 Hz to 70 Hz (30 V to 500 V, 10 mA to 100 A)	Using Power Energy Standard by Direct Method	(-) 180 ° to (+) 180 °	0.006 ° to 0.007 °



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40	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	Power Factor (Lag/Lead) @ 40 Hz to 70 Hz (30 V to 500 V, 10 mA to 100 A)	Using Power Energy Standard by Direct Method	0.1 PF (Lag/Lead) to UPF	0.006 PF to 0.007 PF
41	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	PT Phase Angle @ 50 Hz	Using PT Test Bench with Standard PT by Comparison Method	0 to 360 min	3 min
42	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	PT Ratio @ 50 Hz	Using PT Test Bench with Standard PT by Comparison Method	220V/110V, 63.5V to 33kV/110V, 63.5V	0.2 %
43	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	1 Phase Active Energy @ 40 Hz to 70 Hz (30 V to 500 V, 10 mA to 100 A, 0.1 PF (Lag/Lead) to UPF)	Using Power Energy Calibrator by Direct Method	0.03 Wh to 50 kWh	0.2 % to 0.021 %
44	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	1 Phase Active Power @ 40 Hz to 70 Hz (30 V to 500V, 10 mA to 100 A, 0.1 PF (Lag/Lead) to UPF)	Using Power Energy Calibrator by Direct Method	0.03 W to 50 kW	0.2 % to 0.021 %



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45	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	3 Phase Active Energy @ 40 Hz to 70 Hz (40 V to 300 V, 10 mA to 100 A, 0.1 PF (Lag/Lead) to UPF)	Using Power Energy System by Direct Method	0.04 Wh to 30 kWh	0.2 % to 0.027 %
46	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	3 Phase Active Power @ 40 Hz to 70 Hz (40 V to 300 V, 10 mA to 100 A, 0.1 PF (Lag/Lead) to UPF)	Using Power Energy Calibrator by Direct Method	0.04 W to 30 kW	0.2 % to 0.027 %
47	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 1 kHz to 5 kHz	Using MFC, AC Measurement Standard & Standard Resistor by V/I Method	10 µA to 100 µA	0.2 % to 0.05 %
48	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 1 kHz to 5 kHz	Using MFC, AC Measurement Standard and Current shunt by V/I Method	100 µA to 100 mA	0.05 % to 0.03 %
49	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 1 kHz to 5 kHz	Using MFC & Transconductance Amplifier by V/I Method	100 mA to 20 A	0.03 % to 0.09 %



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50	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 10 Hz to 1 kHz	Using Trans conductance Amplifier, Standard Resistor & 8½ DMM by V/I Method	10 A to 100 A	0.02 % to 0.1 %
51	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 10 Hz to 1 kHz	Using MFC, AC Measurement Standard & Standard Resistor by V/I Method	10 µA to 100 mA	0.01 %
52	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 10 Hz to 1 kHz	Using MFC, AC Measurement Standard and Standard Resistor by V/I Method	100 mA to 10 A	0.01 % to 0.03 %
53	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 5 kHz to 10 kHz	Using MFC by Direct Method	1 mA to 2 A	0.01 % to 0.057 %
54	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 5 kHz to 10 kHz	Using MFC by Direct Method	2 A to 10 A	0.057 % to 0.03 %
55	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 50 Hz	Using MFC with Current coil & CT source by Direct Method	20 A to 3200 A	0.3 %



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56	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Resistance (4 Wire) @ 1 kHz	Using Standard Resistors by Direct Method	0.1 mohm to 1 mohm	0.023 % to 0.017 %
57	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Resistance (4 Wire) @ 1 kHz	Using Standard Resistors by Direct Method	0.1 mohm to 100 mohm	0.02 % to 0.01 %
58	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Resistance (4 Wire) @ 1 kHz	Using Standard Resistors by Direct Method	1 ohm to 10 kohm	0.0008 % to 0.003 %
59	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Resistance (4 Wire) @ 1 kHz	Using Standard Resistors by Direct Method	10 mohm to 100 mohm	0.01 %
60	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Resistance (4 Wire) @ 1 kHz	Using Standard Resistors by Direct Method	10 mohm to 100 mohm	0.012 % to 0.008 %
61	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 10 Hz to 10 kHz	Using MFC by Direct Method	1 mV to 100 mV	0.2 % to 0.015 %



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62	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 10 Hz to 10 kHz	Using MFC by Direct Method	100 mV to 10 V	0.015 % to 0.004 %
63	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 10 kHz to 30 kHz	Using MFC by Direct Method	1 mV to 100 mV	0.16 % to 0.0092 %
64	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 10 kHz to 30 kHz	Using MFC by Direct Method	100 mV to 10 V	0.0092 % to 0.005 %
65	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 100 kHz to 1 MHz	Using MFC by Direct Method	1 mV to 10 V	1.3 % to 0.21 %
66	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 30 kHz to 100 kHz	Using MFC by Direct Method	1 mV to 100 mV	0.3 % to 0.0093 %
67	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 30 kHz to 100 kHz	Using MFC by Direct Method	10 V to 200 V	0.005 % to 0.009 %



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68	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 30 kHz to 100 kHz	Using MFC by Direct Method	100 mV to 10 V	0.0093 % to 0.005 %
69	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 40 Hz to 10 kHz	Using MFC by Direct Method	10 V to 1000 V	0.005 % to 0.009 %
70	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using Standard Capacitor by Direct Method	1 μ F	0.011 %
71	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using 4 Terminal standard Capacitor by Direct Method	1 μ F	0.058 %
72	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using 4 Terminal standard Capacitor by Direct Method	1 mF	0.058 %
73	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using Standard Capacitor by Direct Method	1 pF	0.042 %



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74	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using 4 Terminal standard Capacitor by Direct Method	10 μ F	0.058 %
75	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using 4 Terminal standard Capacitor by Direct Method	10 mF	0.058 %
76	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using Std. Capacitor by Direct Method	10 nF	0.011 %
77	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using Standard Capacitor by Direct Method	10 pF	0.002 %
78	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using 4 Terminal standard Capacitor by Direct Method	100 μ F	0.058 %
79	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using Standard Capacitor by Direct Method	100 nF	0.011 %



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80	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using Standard Capacitor by Direct Method	100 pF	0.001 %
81	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using Standard Capacitor by Direct Method	1000 pF	0.001 %
82	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 100 Hz	Using 4 Terminal standard Capacitor by Direct Method	10 mF	0.1 %
83	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 100 Hz	Using 4 Terminal standard Capacitor by Direct Method	100 mF	0.1 %
84	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 100 Hz	Using 4 Terminal standard Capacitor by Direct Method	1000 mF	0.1 %
85	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	1 H	0.052 %



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86	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	1 mH	0.052 %
87	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	10 H	0.052 %
88	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	10 mH	0.052 %
89	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	100 µH	0.052 %
90	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	100 mH	0.052 %
91	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Phase Angle @ 40 to 70 Hz (30 V to 500 V, 10 mA to 100 A)	Using Power & Energy Calibrator by Direct Method	(+) 180° to (-) 180°	0.017 °



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92	ELECTRO-TECHNICAL- Alternating Current (< 1 GHz) (Source)	Power Factor (Lag/Lead) @ 40 Hz to 70 Hz (30 V to 500 V, 10 mA to 100 A)	Using Power Energy Calibrator by Direct Method	0.1 PF (Lag/Lead) to UPF	0.013 PF
93	ELECTRO-TECHNICAL- DIRECT CURRENT (Measure)	DC Current	Using 8½ DMM and Standard Resistor by V/I Method	1 A to 20 A	0.002 % to 0.006 %
94	ELECTRO-TECHNICAL- DIRECT CURRENT (Measure)	DC Current	Using 8½ DMM and Standard Resistor by V/I Method	1 nA to 100 µA	0.003 % to 0.002 %
95	ELECTRO-TECHNICAL- DIRECT CURRENT (Measure)	DC Current	Using 8½ DMM and Standard Resistor by V/I Method	100 µA to 1 A	0.002 %
96	ELECTRO-TECHNICAL- DIRECT CURRENT (Measure)	DC Current	Using 8½ DMM and Standard Resistor by V/I Method	100 µA to 100 mA	0.002 % to 0.001 %
97	ELECTRO-TECHNICAL- DIRECT CURRENT (Measure)	DC Current	Using 8½ DMM and Standard Resistor by V/I Method	100 A to 500 A	0.01 % to 0.04 %



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98	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using 8½ DMM and Standard Resistor by V/I Method	100 mA to 1 A	0.001 % to 0.002 %
99	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using Electrometer with Standard Resistor by V/I Method	100 pA to 1 nA	0.05 % to 0.003 %
100	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using 8½ DMM and Standard Resistor by V/I Method	20 A to 100 A	0.006 % to 0.01 %
101	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC High Voltage	Using HV Probe with DMM by Direct Method	1 kV to 50 kV	0.1 % to 0.5 %
102	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC High Voltage	Using HV Source with HV Divider by Comparison Method	5 kV to 50 kV	0.1 % to 0.5 %
103	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Resistance (4 wire)	Using DCC Bridge and Standard Resistor by V/I Method	0.1 mohm to 100 mohm	0.001 %



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104	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Resistance (4 wire)	Using DCC Bridge and Standard Resistor by V/I Method	1 ohm to 1 Mohm	0.0003 %
105	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Resistance (4 wire)	Using DCC Bridge & Standard Resistor by V/I Method	100 mohm to 1 ohm	0.001 % to 0.0003 %
106	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Resistance (4 wire) @ 1000 V	Using 8½ DMM, MFC and Standard Resistor by V/I Method	1 Gohm to 1 Tohm	0.001 % to 0.05 %
107	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Resistance (4 wire) @ 1000 V	Using 8½ DMM, MFC & Standard Resistor by V/I Method	1 Mohm to 1 Gohm	0.0003 % to 0.001 %
108	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Resistance (4 wire) @ 5000 V	Using High Resistance Meter by Direct Method	100 Gohm to 1 Tohm	0.04 % to 0.25 %
109	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Voltage	Using Nano voltmeter by Direct Method	1 mV to 100 mV	0.007 % to 0.0005 %



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110	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Voltage	Using Nano voltmeter by Direct Method	10 μ V to 1 mV	0.015 % to 0.007 %
111	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Voltage	Using 8½ DMM, DC Ref. STD, Ref. Divider with Null Detector by Comparison Method	100 mV to 1000 V	0.0005 % to 0.0003 %
112	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MFC by Direct Method	1 A to 20 A	0.002 % to 0.006 %
113	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MFC by Direct Method	10 μ A to 100 μ A	0.003 % to 0.002 %
114	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MFC, 8½ Digit DMM, Standard Resistor by V/I Method	100 μ A to 1 A	0.002 %
115	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using DC High Current Source by Direct Method	100 A to 500 A	0.01 % to 0.04 %



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116	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MFC, 8½ Digit DMM, Standard Resistor by V/I Method	100 pA to 1 nA	0.05 % to 0.003 %
117	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MFC with Transconductance amplifier by Direct Method	20 A to 100 A	0.006 % to 0.01 %
118	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MFC with Current Coil by Direct Method	20 A to 1000 A	0.2 %
119	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC High Voltage	Using HV Source with HV Divider by Direct Method	1 kV to 50 kV	0.05 % to 0.5 %
120	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Power (100 mV to 1000 V, 100 mA to 20 A)	Using MFC by Direct Method	10 mW to 12 kW	0.025 % to 0.07 %
121	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Resistance (4 wire)	Using Standard Resistor by Direct Method	0.1 mohm to 100 mohm	0.001 %



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122	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Resistance (4 wire)	Using Standard Resistor by Direct Method	1 ohm to 1 Mohm	0.0002 % to 0.0005 %
123	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Resistance (4 wire)	Using Standard Resistors by Direct Method	100 mohm to 1 ohm	0.0002 % to 0.001 %
124	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Resistance (4 wire) @ 5000 V	Using Standard Resistor and Decade Resistance Box by V/I Method	1 Mohm to 10 Gohm	0.0005 % to 0.001 %
125	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Resistance (4 wire) @ 5000 V	Using Standard Resistor by Direct Method	10 Gohm to 1 Tohm	0.001 % to 0.2 %
126	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MFC by Direct Method	1 mV to 100 mV	0.002 % to 0.0005 %
127	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MFC by Direct Method	1 V to 10 V	0.0002 % to 0.0001 %



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128	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MFC by Direct Method	10 μ V to 1 mV	0.005 % to 0.002 %
129	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MFC by Direct Method	100 mV to 1000 V	0.0005 % to 0.0003 %
130	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope - Amplitude (Vertical Deflection factor) - 50 ohm	Using MFC by Direct Method	1 mV to 6.5 V	0.17 %
131	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope - Amplitude (Vertical Deflection factor) -1 Mohm	Using MFC by Direct Method	1 mV to 130 V	0.17 %
132	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope - Bandwidth	Using MFC & Signal Generator by Direct Method	10 Hz to 3 GHz	2 % to 5 %
133	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope - Time Base	Using MFC by Direct Method	2 ns to 5 s	0.0011 % to 0.0003 %



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134	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	RF Level / Power @ 10 MHz to 3 GHz	Using RF Power Meter with sensor by Direct Method	(-) 50 dBm to 13 dBm	0.22 dB to 0.28 dB
135	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	RF Level / Power @ 3 GHz to 6 GHz	Using RF Power Meter with sensor by Direct method	(-) 50 dBm to 13 dBm	0.22 dB to 0.26 dB
136	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	RF Level / Power @ 10 MHz to 3 GHz	Using Synthesized Signal Generator by Direct Method	(-) 50 dBm to 13 dBm	0.24 dB to 0.28 dB
137	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	RF Level / Power @ 3 GHz to 6 GHz	Using Synthesized Signal Generator by Direct Method	(-) 50 dBm to 13 dBm	0.24 dB to 0.28 dB
138	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	B - Type Thermocouple	Using 8½ DMM by Direct Method	0 °C to 1800 °C	0.04 °C



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139	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	C - Type Thermocouple	Using 8½ DMM by Direct Method	0 °C to 2320 °C	0.25 °C
140	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	E - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 270 °C to 1000 °C	0.012 °C
141	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	J - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 210 °C to 1200 °C	0.013 °C
142	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	K - Type Thermocouple	Using 8 ½ DMM by Direct Method	(-) 270 °C to 1372 °C	0.03 °C
143	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	L - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 200 °C to 900 °C	0.04 °C
144	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	N - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 270 °C to 1300 °C	0.025 °C



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145	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	R - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 50 °C to 1768 °C	0.035 °C
146	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	RTD (PT 385 - 100 ohm)	Using 8½ DMM by Direct Method	(-) 200 °C to 650 °C	0.01 °C
147	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	RTD (PT 385 - 1000 ohm)	Using 8½ DMM by Direct Method	(-) 200 °C to 650 °C	0.01 °C
148	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	S - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 50 °C to 1768 °C	0.043 °C
149	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	T - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 270 °C to 400 °C	0.038 °C
150	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	U - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 200 °C to 600 °C	0.03 °C



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151	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	B - Type Thermocouple	Using MFC by Direct Method	0 °C to 1820 °C	0.07 °C
152	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	C - Type Thermocouple	Using MFC by Direct Method	0 °C to 2320 °C	0.09 °C
153	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	E - Type Thermocouple	Using MFC by Direct Method	(-) 270 °C to 1000 °C	0.11 °C
154	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	J - Type Thermocouple	Using MFC by Direct Method	(-) 210 °C to 1200 °C	0.08 °C
155	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	K - Type Thermocouple	Using MFC by Direct Method	(-) 270 °C to 1372 °C	0.06 °C
156	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	L - Type Thermocouple	Using MFC by Direct Method	(-) 200 °C to 900 °C	0.02 °C



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157	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	N - Type Thermocouple	Using MFC by Direct Method	(-) 270 °C to 1300 °C	0.06 °C
158	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	R - Type Thermocouple	Using MFC by Direct Method	(-) 50 °C to 1768 °C	0.2 °C
159	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	RTD (PT 385 - 100 ohm)	Using MFC by Direct Method	(-) 199 °C to 650 °C	0.03 °C
160	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	RTD (PT 385 - 1000 ohm)	Using MFC by Direct Method	(-) 199 °C to 650 °C	0.03 °C
161	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	S - Type Thermocouple	Using MFC by Direct Method	(-) 50 °C to 1768 °C	0.2 °C
162	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	T - Type Thermocouple	Using MFC by Direct Method	(-) 270 °C to 400 °C	0.09 °C



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163	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	U - Type Thermocouple	Using MFC by Direct Method	(-) 200 °C to 600 °C	0.02 °C
164	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Time Period	Using Frequency Counter with Rubidium Reference by Direct Method	3.3 ns to 1000 s	0.00000021 %
165	ELECTRO-TECHNICAL-TIME & FREQUENCY (Source)	Frequency	Using Signal Generator with Rubidium Reference by Direct Method	1 mHz to 6 GHz	0.00000003 %
166	ELECTRO-TECHNICAL-TIME & FREQUENCY (Source)	Time	Using Frequency Counter, Rubidium Reference with Signal Generator by Direct Method	3.3 ns to 1000 s	0.0000007 %
167	THERMAL-SPECIFIC HEAT & HUMIDITY	RH & Temperature Indicator with Inbuilt or External sensor, Thermo Hygrometer @ 20 %RH to 95 %RH	Using RH & Temperature Indicator with sensor, Chamber by Comparison Method	25 °C to 55 °C	0.4 °C



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168	THERMAL-SPECIFIC HEAT & HUMIDITY	RH & Temperature Indicator with Inbuilt or External sensor, Thermo Hygrometer @ 25 °C to 55 °C	Using RH & Temperature Indicator with sensor, Chamber by Comparison Method	20 %RH to 95 %RH	1.32 %RH
169	THERMAL-TEMPERATURE	Digital temperature indicator with Sensor of Chamber, Freezer, Bath (Single Position)	Using PRT with DTI by comparison method	(-) 80 °C to 250 °C	0.05 °C
170	THERMAL-TEMPERATURE	Digital Temperature indicator with sensor of Chambers, Baths (Single Position)	Using PRT with DTI by comparison method	250 °C to 600 °C	0.1 °C
171	THERMAL-TEMPERATURE	Liquid in glass thermometer	Using PRT with DTI, Low temperature liquid bath by Comparison Method	(-) 80 °C to 50 °C	0.58 °C
172	THERMAL-TEMPERATURE	Liquid in glass thermometer	Using PRT with DTI, High Temperature oil bath by Comparison Method	50 °C to 250 °C	0.58 °C
173	THERMAL-TEMPERATURE	RTD with indicator	Using PRT with DTI and Oil bath by Comparison Method	(-) 80 °C to 250 °C	0.083 °C
174	THERMAL-TEMPERATURE	RTD with indicator	Using PRT with DTI and Dry Block calibrator by Comparison Method	250 °C to 600 °C	0.19 °C



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175	THERMAL-TEMPERATURE	Thermocouple with indicator	Using S type Thermocouple with DTI and Dry block furnace by Comparison Method	300 °C to 1000 °C	1.39 °C
176	THERMAL-TEMPERATURE	Thermocouple with indicator	Using PRT with DTI and Dry block furnace by Comparison Method	50 °C to 600 °C	0.18 °C



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Site Facility					
1	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	1 Phase AC Active Energy @ 40 Hz to 70 Hz (40 V to 320 V, 10 mA to 20 A, 0.1 PF (lag/Lead) to UPF)	Using Power Analyzer by Direct Method	0.04 Wh to 6.4 kWh	0.031 %
2	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	1 Phase AC Active Power @ 40 Hz to 70 Hz (40 V to 320 V, 10 mA to 20 A, 0.1 PF (lag/Lead) to UPF)	Using Power Analyzer by Direct Method	0.04 W to 6.4 kW	0.03 %
3	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	3 Phase AC Active Power @ 40 Hz to 70 Hz (40 V to 320 V, 10 mA to 20 A, 0.1 PF (Lag/Lead) to UPF)	Using Power Energy Calibrator by Direct Method	0.04 W to 6.4 kW	0.03 %
4	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 50 Hz to 1 KHz	Using 8½ DMM and Standard Resistor by V/I Method	20 A to 100 A	0.05 %



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5	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 50 Hz to 5 KHz	Using 8½ DMM and Standard Resistor by V/I Method	1 A to 20 A	0.08 %
6	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current @ 50 Hz to 5 kHz	Using 8½ DMM and Standard Resistor by V/I Method	100 mA to 1 A	0.04 % to 0.08 %
7	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC High Voltage @ 50 Hz	Using HV Probe with DMM by Direct Method	1 kV to 5 kV	1 %
8	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC High Voltage @ 50 Hz	Using HV Probe with DMM by Direct Method	5 kV to 28 kV	1 % to 2 %
9	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Resistance 4wire @ 1 KHz	Using Precision Component Analyser by Direct Method	1 ohm to 5 Mohm	0.02 % to 0.1 %



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10	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 10 kHz	Using 8½ DMM by Direct Method	10 mV to 100 mV	0.03 % to 0.012 %
11	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 10 kHz to 30 kHz	Using 8½ DMM by Direct Method:	100 mV to 1000 V	0.034 % to 0.022 %
12	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 30 kHz	Using 8½ DMM by Direct Method	10 mV to 100 mV	0.07 % to 0.034 %
13	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 30 kHz to 100 kHz	Using 8½ DMM by Direct Method	10 mV to 100 mV	0.17 % to 0.08 %
14	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 30 kHz to 100 kHz	Using 8½ DMM by Direct Method	100 mV to 100 V	0.08 % to 0.06 %



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15	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage @ 50 Hz to 10 kHz	Using 8½ DMM by Direct Method	100 mV to 1000 V	0.012 % to 0.01 %
16	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	Capacitance @ 1 kHz	Using Precision Component Analyser by Direct Method	10 pF to 1 mF	0.05 % to 0.2 %
17	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	Inductance @ 1 kHz	Using Precision Component Analyser by Direct Method	10 µH to 10 H	0.052 % to 0.2 %
18	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	Phase Angle @ 40 Hz to 70 Hz (40 V to 320 V, 5 mA to 20 A)	Using Power Energy Standard by Direct Method	(-) 180 ° to (+)180 °	0.028 °
19	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	1 Phase Active Energy @ 40 Hz to 70 Hz (40 V to 320 V, 10 mA to 20 A, 0.1 PF (Lag/Lead) to UPF)	Using Power Energy Calibrator by Direct Method	0.04 Wh to 6.4 kWh	0.031 % to 0.31 %



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20	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	1 Phase Active Power @ 40 to 70 Hz (40 V to 320 V, 10 mA to 20 A, 0.1 PF (Lag/Lead) to UPF)	Using Power Energy Calibrator by Direct Method	0.04 W to 6.4 kW	0.03 % to 0.31 %
21	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 1 kHz to 5 kHz	Using MFC by Direct Method	1 A to 20 A	0.7 % to 3.2 %
22	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 1 kHz to 5 kHz	Using Multifunction Calibrator & Multifunction Transfer Standard by Direct Method	1 mA to 10 mA	0.22 % to 0.1 %
23	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 1 kHz to 5 kHz	Using MFC by Direct Method	10 mA to 100 mA	0.1 % to 0.15 %
24	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 1 kHz to 5 kHz	Using Multifunction Calibrator & Multifunction Transfer Standard by V/I Method	100 µA to 1 mA	0.45 % to 0.22 %
25	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 1 kHz to 5 kHz	Using MFC by Direct Method	100 mA to 1 A	0.15 % to 0.7 %



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26	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 50 Hz	Using MFC with Current Coil by Direct Method	20 A to 1000 A	0.3 %
27	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 50 Hz to 1 kHz	Using MFC by Direct Method	1 A to 10 A	0.06 % to 0.08 %
28	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 50 Hz to 1 kHz	Using MFC by Direct Method	1 mA to 10 mA	0.12 % to 0.06 %
29	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 50 Hz to 1 kHz	Using MFC by Direct Method	10 A to 20 A	0.08 % to 0.15 %
30	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 50 Hz to 1 kHz	Using MFC by Direct Method	10 mA to 1 A	0.06 %
31	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current @ 50 Hz to 1 kHz	Using MFC by Direct Method	100 µA to 1 mA	0.23 % to 0.12 %



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32	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Resistance (4 Wire) @ 1 kHz	Using Standard Resistors by Direct Method	1 ohm to 10 kohm	0.004 %
33	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Resistance (4 Wire) @ 1 kHz	Using Standard Resistors by Direct Method	10 mohm to 100 mohm	0.01 %
34	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 10 kHz to 30 kHz	Using MFC by Direct Method	1 mV to 10 mV	0.7 % to 0.11 %
35	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 10 kHz to 30 kHz	Using MFC by Direct Method	10 mV to 100 mV	0.11 % to 0.036 %
36	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 10 kHz to 30 kHz	Using MFC by Direct Method	10 V to 100 V	0.03 % to 0.036 %
37	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 10 kHz to 30 kHz	Using MFC by Direct Method	100 mV to 10 V	0.036 % to 0.03 %



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38	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 100 kHz to 500 kHz	Using MFC by Direct Method	1 mV to 10 V	5.8 % to 0.25 %
39	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 30 kHz to 100 kHz	Using MFC by Direct Method	1 mV to 10 mV	1.5 % to 0.5 %
40	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 30 kHz to 100 kHz	Using MFC by Direct Method	10 mV to 100 mV	0.5 % to 0.083 %
41	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 30 kHz to 100 kHz	Using MFC by Direct Method	10 V to 100 V	0.041 % to 0.25 %
42	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 30 kHz to 100 kHz	Using MFC by Direct Method	100 mV to 10 V	0.083 % to 0.041 %
43	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 50 Hz to 10 kHz	Using MFC by Direct Method	1 mV to 10 mV	0.62 % to 0.075 %



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44	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 50 Hz to 10 kHz	Using MFC by Direct Method	10 mV to 100 mV	0.075 % to 0.025 %
45	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 50 Hz to 10 kHz	Using MFC by Direct Method	10 V to 1000 V	0.021 % to 0.031 %
46	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage @ 50 Hz to 10 kHz	Using MFC by Direct Method	100 mV to 10 V	0.025 % to 0.021 %
47	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using 4 Terminal standard Capacitor by Direct Method	1 μ F	0.02 %
48	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using Standard Capacitor by Direct Method	1 pF	0.04 %
49	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using 4 Terminal standard Capacitor by Direct Method	10 μ F	0.02 %



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50	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using 4 Terminal standard Capacitor by Direct Method	10 mF	0.1 %
51	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using Std. Capacitor by Direct Method	10 pF to 1 µF	0.02 %
52	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using 4 Terminal standard Capacitor by Direct Method	100 µF	0.1 %
53	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 100 Hz	Using 4 Terminal standard Capacitor by Direct Method	10 mF	0.1 %
54	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 100 Hz	Using 4 Terminal standard Capacitor by Direct Method	100 mF	0.1 %
55	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 100 Hz	Using 4 Terminal standard Capacitor by Direct Method	1000 mF	0.1 %



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56	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	1 H	0.055 %
57	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	1 mH	0.052 %
58	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	10 H	0.055 %
59	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	10 mH	0.052 %
60	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	100 µH	0.052 %
61	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Standard Inductor by Direct Method	100 mH	0.055 %



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62	ELECTRO-TECHNICAL- Alternating Current (< 1 GHz) (Source)	Phase Angle/ @ 40 Hz to 70 Hz (40 V to 320 V, 5 mA to 100 A)	Using Power & Energy Calibrator by Direct Method	(-) 180 ° to (+) 180 °	0.028 °
63	ELECTRO-TECHNICAL- DIRECT CURRENT (Measure)	DC Current	Using 8½ DMM by Direct Method	10 mA to 100 mA	0.003 % to 0.004 %
64	ELECTRO-TECHNICAL- DIRECT CURRENT (Measure)	DC Current	Using 8½ DMM by Direct Method	100 µA to 10 mA	0.003 %
65	ELECTRO-TECHNICAL- DIRECT CURRENT (Measure)	DC Current	Using 8½ DMM by Direct Method	100 mA to 1 A	0.004 % to 0.012 %
66	ELECTRO-TECHNICAL- DIRECT CURRENT (Measure)	DC High Voltage	Using HV Probe with DMM by Direct Method	1 kV to 50 kV	0.2 % to 1%
67	ELECTRO-TECHNICAL- DIRECT CURRENT (Measure)	DC High Voltage	Using HV Probe with DMM by Direct Method	5 kV to 40 kV	0.2 % to 1 %



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68	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Resistance (4 wire)	Using 8½ DMM by Direct Method	1 ohm to 10 ohm	0.0075 % to 0.001 %
69	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Resistance (4 wire)	Using 8½ DMM by Direct Method	10 ohm to 100 Mohm	0.001 % to 0.002 %
70	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Resistance (4 wire)	Using 8½ DMM by Direct Method	100 Mohm to 1 Gohm	0.002 % to 0.012 %
71	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Resistance (4 wire)	Using Micro ohm meter by Direct Method	100 mohm to 1 ohm	0.01 % to 0.0075 %
72	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Resistance (4 wire) @ 1000 V	Using High Resistance Meter by Direct Method	1 Gohm to 100 Gohm	0.012 % to 0.04 %
73	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Voltage	Using 8½ DMM by Direct Method	1 mV to 10 mV	0.007 % to 0.0055 %



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74	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Voltage	Using 8½ DMM by Direct Method	10 mV to 100 mV	0.0055 % to 0.0008 %
75	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Voltage	Using 8½ DMM by Direct Method	100 mV to 1000 V	0.0008 % to 0.0012 %
76	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MFC by Direct Method	1 A to 20 A	0.025 % to 0.11 %
77	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MFC by Direct Method	1 mA to 100 mA	0.017 % to 0.013 %
78	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MFC by Direct Method	100 µA to 1 mA	0.04 % to 0.017 %
79	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MFC by Direct Method	100 mA to 1 A	0.013 % to 0.025 %



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80	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MFC with Current Coil by Direct Method	20 A to 1000 A	0.3 %
81	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Power (1 V to 1000 V & 100 mA to 20 A)	Using MFC by Direct Method	10 mW to 12 kW	0.025 % to 0.07 %
82	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Resistance (4 wire)	Using Standard Resistor by Direct Method	1 mohm to 10 kohm	0.001 %
83	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Resistance (4 wire)	Using Decade Resistance Box by Direct Method	1 Mohm to 10 Mohm	0.001 % to 0.005 %
84	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Resistance (4 wire)	Using Standard Resistor and Decade Resistance Box by Direct Method	10 kohm to 1 Mohm	0.001 %
85	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Resistance (4 wire)	Using Decade Resistance Box by Direct Method	10 Mohm to 1 Gohm	0.005 % to 0.08 %



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86	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Resistance (4 wire) @ 5000 V	Using Decade Resistance Box by Direct Method	1 Gohm to 1 Tohm	0.05 % to 0.4 %
87	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MFC by Direct Method	1 mV to 100 mV	0.1 % to 0.003 %
88	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MFC by Direct Method	100 mV to 1000 V	0.003 % to 0.002 %
89	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope - Amplitude (Vertical Deflection Factor) - 50 ohm	Using MFC by Direct Method	1 mV to 6.5 V	0.46 %
90	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope - Amplitude (Vertical Deflection Factor) -1 Mohm	Using MFC by Direct Method	1 mV to 130 V	1 %
91	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope - Bandwidth	Using Signal Generator & MFC by Direct Method	10 Hz to 3 GHz	3 % to 5 %



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92	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope - Time Base	Using MFC by Direct Method	2 ns to 5 s	0.0011 % to 0.0003 %
93	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	RF Level / Power @ 10 MHz to 3 GHz	Using RF Power Meter with sensor by Direct Method	(-) 50 dBm to 13 dBm	0.22 dB to 0.26 dB
94	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	RF Level / Power @ 3 GHz to 6 GHz	Using RF Power Meter with sensor by Direct Method	(-) 50 dBm to 13 dBm	0.22 dBm to 0.26 dBm
95	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	RF Level / Power @ 10 MHz to 3 GHz	Using Synthesized Signal Generator by Direct Method	(-) 50 dB to 13 dB	0.24 dB to 0.28 dB
96	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	RF Level / Power @ 3 GHz to 6 GHz	Using Synthesized Signal Generator by Direct Method	(-) 50 dB to 13 dB	0.24 dB to 0.28 dB



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97	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	B - Type Thermocouple	Using 8½ DMM by Direct Method	600 °C to 1800 °C	0.04 °C
98	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	C - Type Thermocouple	Using 8½ DMM by Direct Method	0 °C to 2300 °C	0.9 °C
99	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	E - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 250 °C to 400 °C	0.038 °C
100	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	E - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 250 °C to 1000 °C	0.012 °C
101	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	J - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 200 °C to 1200 °C	0.013 °C
102	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	K - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 200 °C to 1350 °C	0.03 °C



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103	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	L - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 200 °C to 900 °C	0.4 °C
104	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	N - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 200 °C to 1300 °C	0.025 °C
105	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	R - Type Thermocouple	Using 8½ DMM by Direct Method	0 °C to 1750 °C	0.035 °C
106	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	RTD (PT 385 - 100 ohm)	Using 8½ DMM by Direct Method	(-) 199 °C to 800 °C	0.04 °C
107	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	RTD (PT 385 - 1000 ohm)	Using 8½ DMM by Direct Method	(-) 199 °C to 800 °C	0.04 °C
108	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	S - Type Thermocouple	Using 8½ DMM by Direct Method	0 °C to 1750 °C	0.15 °C



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109	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	S - Type Thermocouple	Using 8½ DMM by Direct Method	0 °C to 1750 °C	0.043 °C
110	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	U - Type Thermocouple	Using 8½ DMM by Direct Method	(-) 200 °C to 600 °C	0.6 °C
111	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	B - Type Thermocouple	Using MFC by Direct Method	600 °C to 1800 °C	0.15 °C
112	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	C - Type Thermocouple	Using MFC by Direct Method	0 °C to 2300 °C	0.9 °C
113	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	E - Type Thermocouple	Using MFC by Direct Method	(-) 250 °C to 1000 °C	0.11 °C
114	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	J - Type Thermocouple	Using MFC by Direct Method	(-) 200 °C to 1200 °C	0.08 °C



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115	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	K - Type Thermocouple	Using MFC by Direct Method	(-) 200 °C to 1350 °C	0.11 °C
116	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	L - Type Thermocouple	Using MFC by Direct Method	(-) 200 °C to 900 °C	0.4 °C
117	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	N - Type Thermocouple	Using MFC by Direct Method	(-) 200 °C to 1300 °C	0.025 °C
118	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	R - Type Thermocouple	Using MFC by Direct Method	0 °C to 1750 °C	0.15 °C
119	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	RTD (PT 385 - 100 ohm & 1000 ohm)	Using MFC by Direct Method	(-) 199 °C to 800 °C	0.03 °C
120	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	T - Type Thermocouple	Using MFC by Direct Method	(-) 250 °C to 400 °C	0.13 °C



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121	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	U - Type Thermocouple	Using MFC by Direct Method	(-) 200 °C to 600 °C	0.6 °C
122	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Frequency	Using Frequency Counter by Direct Method	1 Hz to 18 GHz	0.00003 %
123	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Frequency	Using Frequency Counter by Direct Method	1 kHz to 15 GHz	0.0000002 %
124	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Time Period	Using Frequency Counter by Direct Method	1 μ s to 1000 s	0.00000097 %
125	ELECTRO-TECHNICAL-TIME & FREQUENCY (Source)	Frequency	Using Signal Generator by Direct Method	1 Hz to 6 GHz	0.00003 %
126	ELECTRO-TECHNICAL-TIME & FREQUENCY (Source)	Time	Using Signal Generator by Direct Method	1 μ s to 1000 s	0.00003 %



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127	THERMAL-SPECIFIC HEAT & HUMIDITY	RH &Temperature Indicator with Inbuilt or External sensor, Thermo-Hygrometer @ 25 °C to 55 °C	Using RH / Temperature indicator with sensor by Comparison Method	20 % RH to 95 %RH	1.5 % RH
128	THERMAL-TEMPERATURE	RTD with indicator	Using PRT with DTI and Dry Block Calibrator by Comparison Method	(-) 25 °C to 600 °C	0.2 °C
129	THERMAL-TEMPERATURE	Temperature Indicator with sensor of Oven, Deep freezer, Chamber (Single Position)	Using RTD (PT-100) with DTI by Comparison Method	(-) 80 °C to 200 °C	0.5 °C
130	THERMAL-TEMPERATURE	Temperature Indicator with sensor of Oven, Dry Block, chamber (Single Position)	Using S type Thermocouple with DTI by Comparison Method	300 °C to 1000 °C	1.39 °C
131	THERMAL-TEMPERATURE	Temperature Indicator with sensor of Oven, Oil bath, Dry Block, chamber (Single Position)	Using PRT with DTI by Comparison Method	(-) 25 °C to 600 °C	0.2 °C

* CMCs represent expanded uncertainties expressed at approximately the 95% level of confidence, using a coverage factor of $k = 2$.